

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination INNES ET AL.	
		Examiner Jonathan G. Sterrett	Art Unit 3623	Page 1 of 1

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Breitfelder, Kim; Messina, Don; "The Authoritative Dictionary of IEEE Standards Terms", 7th Edition, Copyright 2000, IEEE Press, p. 270.
V	Merriam-Websters Collegiate Dictionary, 10th edition, Copyright 1997, p.1 & 746.
W	Gilchrist, Warren, "Modelling failure modes and effects analysis", 1993, The International Journal of Quality and Reliability Management, Bradford, Vol. 10, Iss 5, p.16, ProQuest ID 1123094.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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